

Super Junction MOSFETs



Lead Free Package and Finish

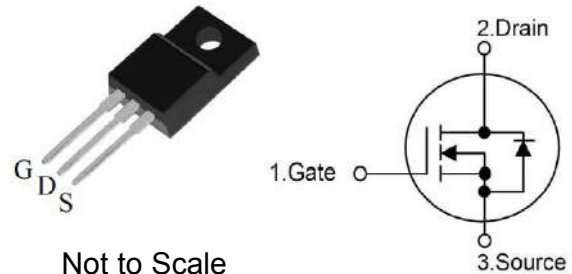
Applications:

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply(UPS)
- PFC stages for server & telecom
- Consumer

Features:

- New revolutionary high voltage technology
- Better RDS(on) in TO-220F
- Ultra Low Gate Charge cause lower driving requirements
- Periodic avalanche rated
- Ultra low effective capacitances

| | | |
|----|---------------|------|
| ID | RDS(ON)(Max.) | Vdss |
| 7A | 650mΩ | 650V |



Ordering Information

| Part Number | Package | Marking |
|-------------|---------|----------|
| RSU7N65F | TO-220F | RSU7N65F |

Absolute Maximum Ratings Tc=25°C unless otherwise specified

| Symbol | Parameter | RSU7N65F | Units |
|-------------|---|------------|-------|
| VDSS | Drain-to-Source Voltage | 650 | V |
| ID | Continuous Drain Current (TC = 25°C) | 7 | A |
| | Continuous Drain Current (TC = 100°C) | 4 | |
| IDM | Pulsed Drain Current (Note*1) | 21 | |
| PD | Power Dissipation(Tc=25°C) | 32 | W |
| VGS | Gate-to-Source Voltage | ±30 | V |
| EAS | Single Pulse Avalanche Energy (Note*2) | 120 | mJ |
| IAR | Avalanche Current pulse width limited by maximum junction temperature. | 1.2 | A |
| TL TPKG | Maximum Temperature for Soldering | | °C |
| | Leads at 0.063in(1.6mm)from Case for 10 seconds | 300 | |
| | Package Body for 10 seconds | 260 | |
| TJ and TSTG | Operating Junction and Storage Temperature Range | -55 to 150 | |

*Drain Current Limited by Maximum Junction Temperature

Caution:Stresses greater than those listed in the“Absolute Maximum Ratings”Table may cause permanent damage to the device.

Thermal Resistance

| Symbol | Parameter | RSU7N65F | Units | Test Conditions |
|--------|---------------------|----------|-------|--|
| RθJC | Junction-to-Case | 4 | °C/W | Drain lead soldered to water cooled heatsink,PD Adjusted for a peak junction temperature of +150°C. |
| RθJA | Junction-to-Ambient | 68 | | 1 cubic foot chamber,free air. |

OFF Characteristics TJ=25°C unless otherwise specified

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|-----------------------------------|------|------|------|-------|---------------------------------|
| BVDSS | Drain-to-source Breakdown Voltage | 650 | -- | -- | V | VGS = 0V, ID = 250μA, TJ= 25°C |
| | | -- | 650 | -- | V | VGS = 0V, ID = 250μA, TJ= 150°C |
| IDSS | Drain-to-Source Leakage Current | -- | -- | 1.0 | μA | VDS=650V, VGS=0V |
| IGSS | Gate-to-Source Forward Leakage | -- | -- | 100 | nA | VGS=+30V VDS=0V |
| | Gate-to-Source Reverse Leakage | -- | -- | -100 | | VGS=-30V VDS=0V |

ON Characteristics TJ=25°C unless otherwise specified

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|---------|--------------------------------------|------|------|------|-------|-------------------|
| RDS(on) | Static Drain-to-Source On-Resistance | -- | 560 | 650 | mΩ | VGS=10V, ID=3.5A |
| VGS(TH) | Gate Threshold Voltage | 2.5 | -- | 4.0 | V | VGS=VDS, ID=250μA |

Resistive Switching Characteristics Essentially independent of operating temperature

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|---------|---------------------|------|------|------|-------|--|
| td(ON) | Turn-on Delay Time | -- | 11.6 | -- | ns | VDS=400V ID=3.5A RG=25Ω VGS=10V |
| trise | Rise Time | -- | 23 | -- | | |
| td(OFF) | Turn-OFF Delay Time | -- | 53 | -- | | |
| tfall | Fall Time | -- | 35.8 | -- | | |

Dynamic Characteristics Essentially independent of operating temperature

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|--------------------------------|------|------|------|-------|--------------------------------|
| Ciss | Input Capacitance | -- | 493 | -- | pF | VGS=0V VDS=100V f=1.0MHz |
| Coss | Output Capacitance | -- | 32 | -- | | |
| Crss | Reverse Transfer Capacitance | -- | 1.6 | -- | | |
| Qg | Total Gate Charge | -- | 2.8 | -- | nC | VDS=520V ID=3.5A VGS=10V |
| Qgs | Gate-to-Source Charge | -- | 4.7 | -- | | |
| Qgd | Gate-to-Drain("Miller") Charge | -- | 13.3 | -- | | |

Source-Drain Diode Characteristics

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|-------------------------------|------|------|------|-------|--|
| IS | Continuous Source Current | -- | -- | 7 | A | Integral pn-diode in MOSFET |
| ISM | Maximum Pulsed Current | -- | -- | 21 | A | |
| VSD | Diode Forward Voltage | -- | 0.85 | -- | V | IS=3.5A, VGS=0V Tj=25°C |
| trr | Reverse Recovery Time | -- | 201 | -- | nS | VR=50V, VGS=0V IS=3.5A, di/dt=100A/ μs |
| Qrr | Reverse Recovery Charge | -- | 1.3 | -- | μC | |
| Irrm | Peak Reverse Recovery Current | -- | 11.5 | -- | A | |

Notes:

- *1. Repetitive rating; pulse width limited by maximum junction temperature.
- *2. Pulse width tp limited by Tj,max

Electrical Characteristics Diagrams

Figure 1. Output Characteristics

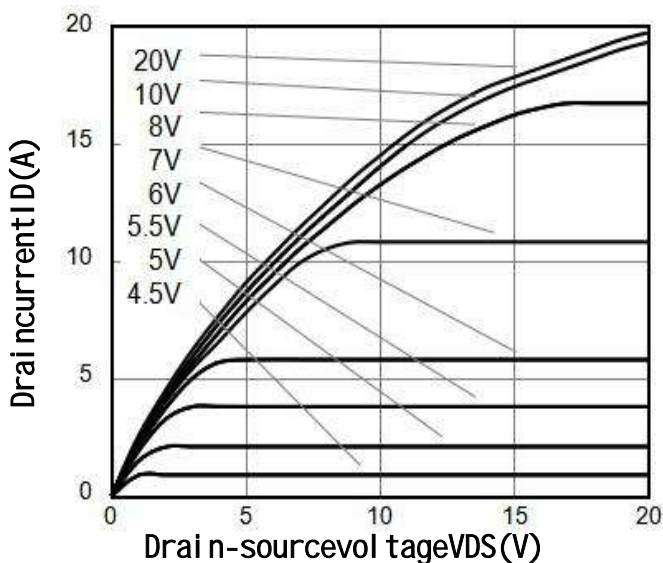


Figure 2. Transfer Characteristics

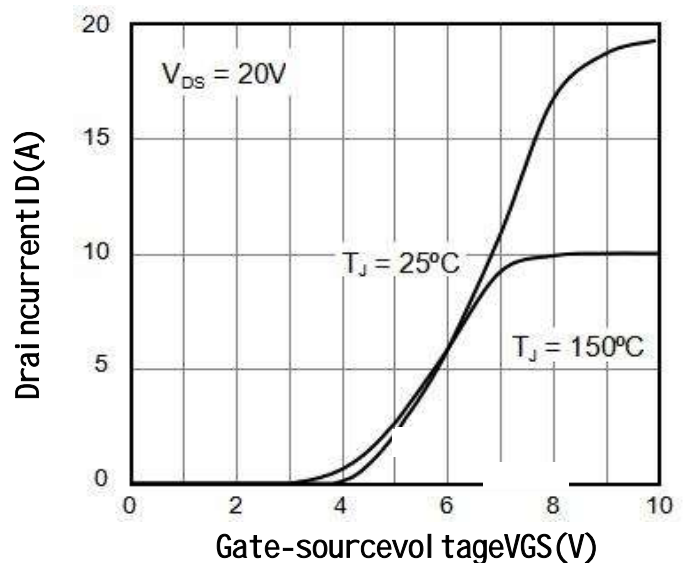


Figure 3. On-Resistance vs. Drain Current

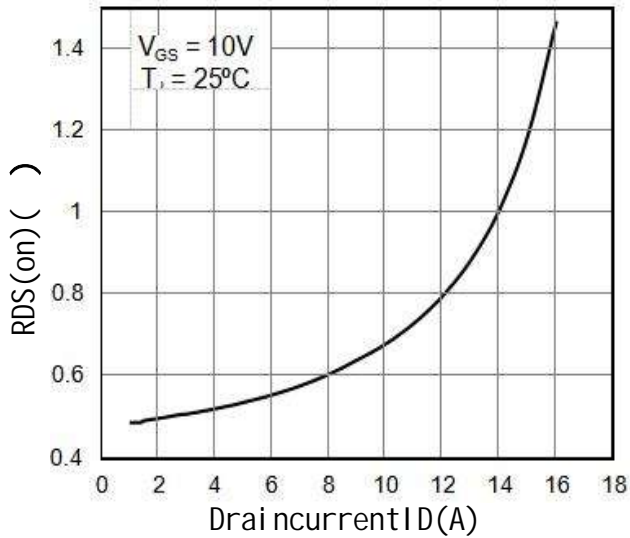


Figure 4. Capacitance Characteristics

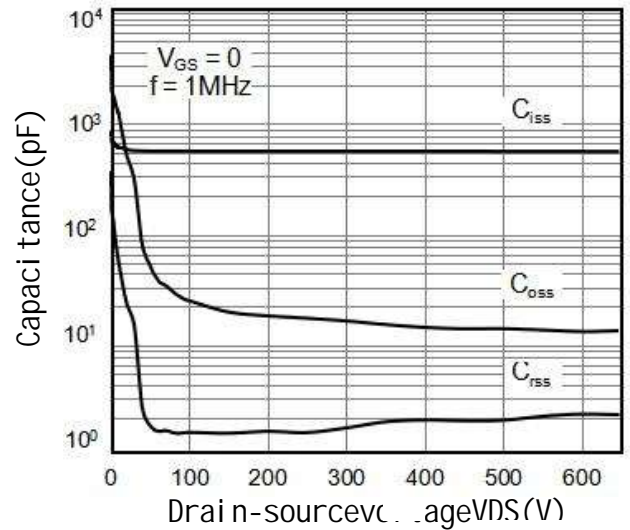


Figure 5. Gate Charge Characteristics

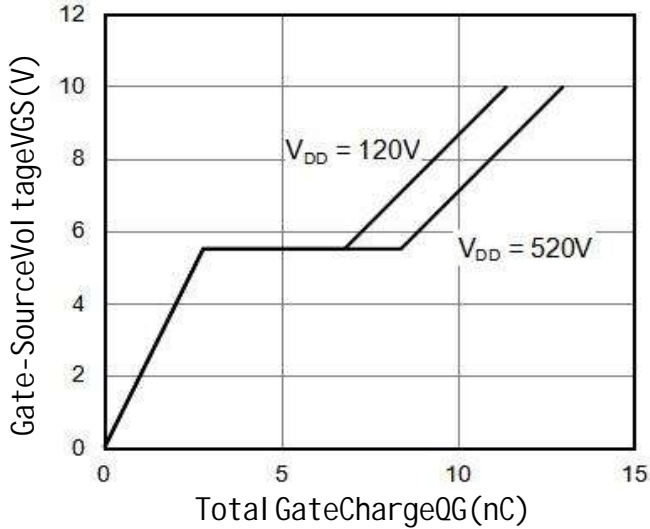


Figure 6. Body Diode Forward Voltage

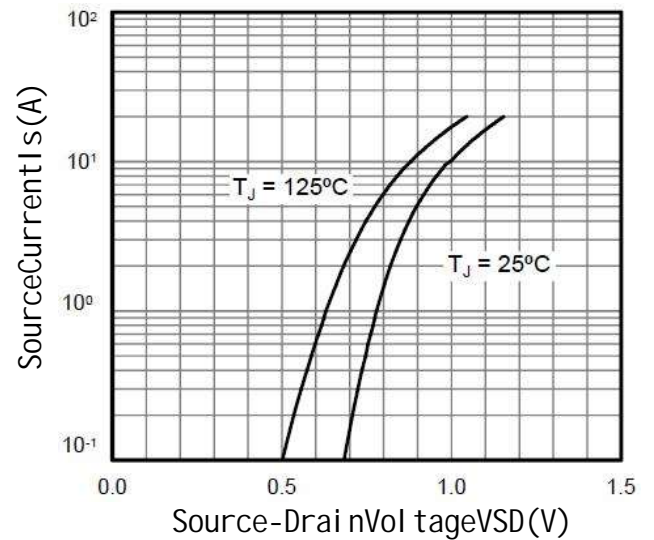


Figure 7. Breakdown Voltage vs. Temperature

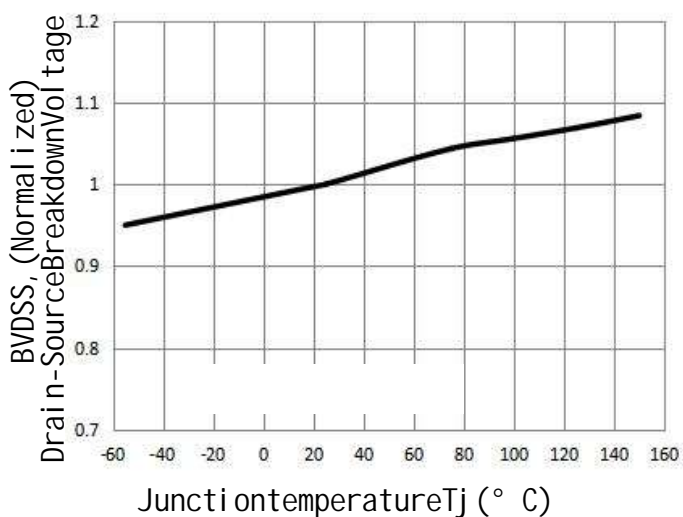


Figure 8. On-Resistance vs. Temperature

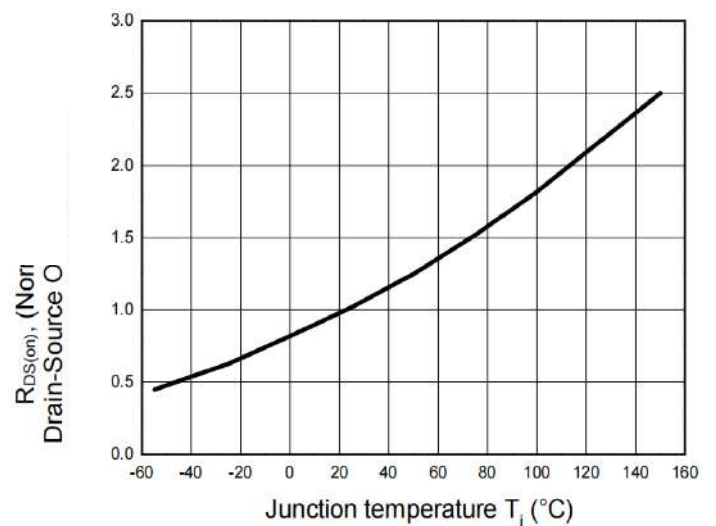
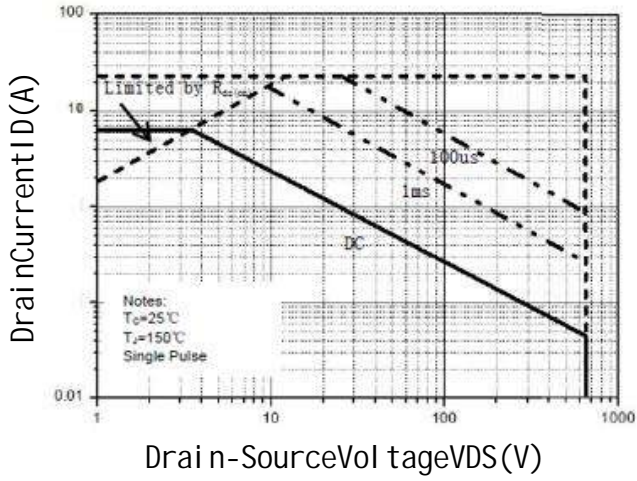
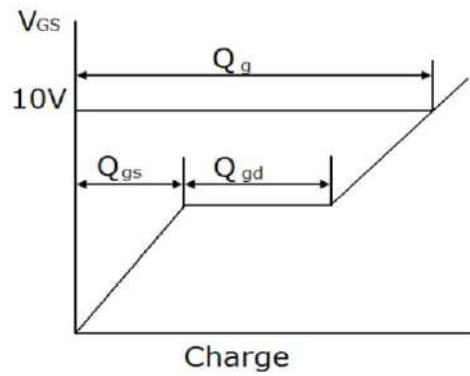
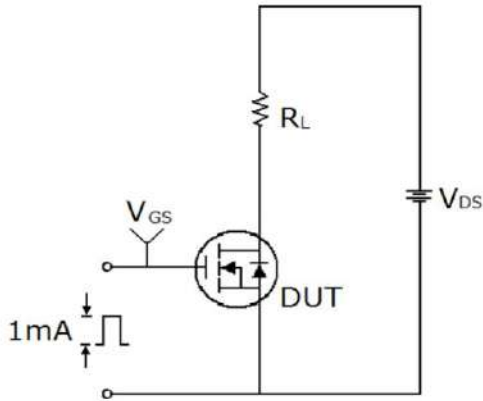


Figure 9. Maximum Safe Operating Area

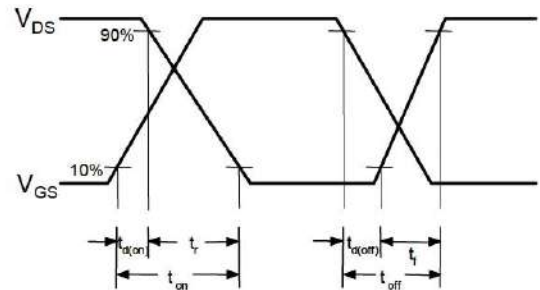
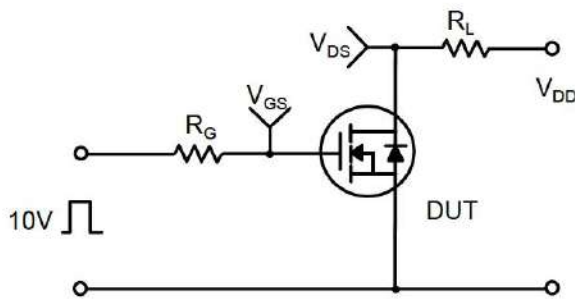


Test Circuits and Waveforms

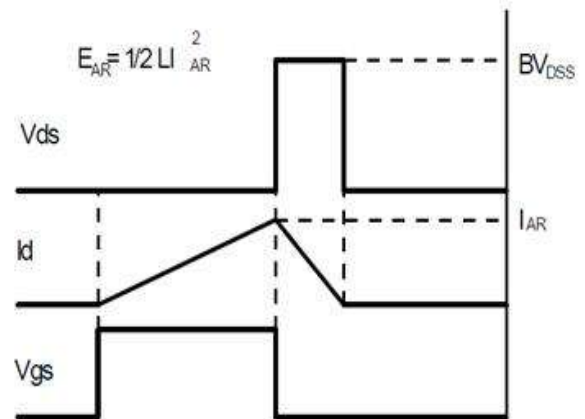
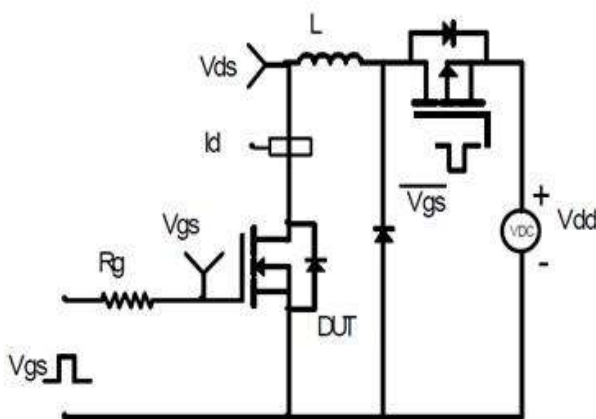
GateChargeTestCircuit&Waveform



SwitchingTestCircuit&Waveform



UnclampedInductiveSwitchingTestCircuit&Waveform



Disclaimers:

Reasunos Semiconductor Technology CO.,LTD(Reasunos)reserves the right to make changes without notice in order to improve reliability,function or design and to discontinue any product or service without notice .Customers should obtain the latest relevant information before orders and should verify that such information in current and complete.All products are sold subject to Reasunos's terms and conditions supplied at the time of order acknowledgement.

Reasunos Semiconductor Technology CO.,LTD warrants performance of its hardware products to the specifications at the time of sale.Testing, reliability and quality control are used to the extene Reasunos deems necessary to support this warrantee. Except where agreed upon by contractual agreement,testing of all parameters of each product is not necessarily performed.

Reasunos Semiconductor Technology CO.,LTD does not assume any liability arising from the use of any product or circuit designs described herein.Customers are responsible for their products and applications using Reasunos's components.To minimize risk,customers must provide adequate design and operating safeguards.

Reasunos Semiconductor Technology CO.,LTD does not warrant or convey any license either expressed or implied under its patent rights,nor the rights of others.Reproduction of information in Reasunos's data sheeets or data books is permissible only if reproduction is without modification oralteration.Reproduction of this information with any alteration is an unfair and deceptive business practice. Reasunos Semiconductor Technology CO.,LTD is not responsible or liable for such altered documentation.

Resale of Reasunos's products with statements different from or beyond the parameters stated by Reasunos Semiconductor Technology CO.,LTD for that product or service voids all express or implied warranties for the associated Reasunos's product or service and is unfair and deceptive business practice. Reasunos Semiconductor Technology CO.,LTD is not responsible or liable for such statements.

Life Support Policy:

Reasunos Semiconductor Technology CO.,LTD's Products are not authorized for use as critical components in life support devices or systems without the expressed written approval of Reasunos Semiconductor Technology CO.,LTD.

As used herein:

- 1.Life support devices or systems are devices or systems which:
 - a.are intended for surgical implant into the human body,
 - b.support or sustain life,
 - c.whose failuer to when properly used in accordance with instructions for used provided in the laeling,can be reasonably expected to result in significant injury to the user.

system whose failure to perform can be reasonably expected to cause the failure of the life support device or system,or to affect its safety or effectiveness.
